

Wednesday 25<sup>th</sup> May 2005

## D/TEC-QCA Final Presentation Day

09:30 - 10:55

- 09:30**    **Welcome & Overview – Reno Harboe-Sørensen**
- 09:40**    **Application-like Radiation Test of XTMR & FTMR Mitigation Techniques for Xilinx Virtex-II FPGA.**  
*Saab Ericsson Space, Sweden – Fredrik Stureson / Stanley Mattsson*
- 10:00**    **Co-60 TID Evaluation of SDRAMs from Elpida, EDS2508APTA 256 Mbit, from Samsung, K4S510432B 512 Mbit and from Micron, MT48LC16M8A2 128 Mbit, using Auto & Self-refresh Mode of Bias Operation.**  
*HIREX Engineering, France – François-Xavier Guerre / J-F Pascal*
- 10:10**    **RADFET Read-out Systems for Ground Calibration and Biopan-4 Experiment.**  
*Tyndall National Institute, Ireland – Aleksandar Jaksic / Vladimir Ogourtsov*
- 10:35**    **Heavy Ion Characterisation of AC/HC Logic Circuits at 2.5 V, 3.3 V and 5.0 V from STM and NS Using : 54AC/HC08, 54AC/HC157, 54AC/HC273, 54AC257, 54AC244, 54HC4040 & 54HC4053 Types.**  
*Saab Ericsson Space, Sweden – Sture Larsson / Stanley Mattsson*
- 10:55**    **Coffee Break**



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11:10 - 12:30

- 11:10**     **Random Telegraph Signals in CCDs and Active Pixel Sensors.**  
*Sira Technology Ltd., UK – Gordon R Hopkinson*
- 11:25**     **Radiation Co-60 TID Evaluation of 16 bit Analog-to-Digital Converters :**  
**Texas Instruments ADS8402, Analog Devices AD7677 & AD9260.**  
*HIREX Engineering, France – François-Xavier Guerre / J-F Pascal*
- 11:35**     **Heavy Ion Effects on Low Voltage LVDS Line Driver / Receiver from NS.**  
*Saab Ericsson Space, Sweden – Sture Larsson / Stanley Mattsson*
- 11:45**     **SEE and TID Acceptance Tests of the Radiation Test-Bed for High Capacity Memory Components.**  
*IDA, Germany – H Schmidt / M Brüggemann / H Michalik / T Fichna*
- 12:00**     **High Energy Proton Damage Assessment of 90 nm node Multiple Gate Oxide Thickness Transistors.**  
*IMEC, Belgium – Eddy Simoen / M-L David / C Claeys*
- 12:30**     **Lunch Break**



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14:00 - 15:30

- 14:00**     **Heavy Ion Effects in UCC1806 and UC1825A Pulse Width Modulators.**  
*Saab Ericsson Space, Sweden – Sture Larsson / Stanley Mattsson*
- 14:20**     **Laser Simulation of Single Event Effects in Pulse Width Modulators and Memories.**  
*MBDA UK Ltd., UK – Andrew Chugg*
- 14:40**     **Construction Analysis of UCC1806 and UC1825A Pulse Width Modulators.**  
*Tyndall National Institute, Ireland – Ted O'Shea / Richard Fitzgerald*
- 15:00**     **SEE Characterisation of Parts for the ATV Project : UC1706 Dual Output Driver, OP400Y Operational Amplifier and M27C512 UV EPROM.**  
*HIREX Engineering, France – François-Xavier Guerre*
- 15:20**     **Heavy Ion SEL Test for the RAL CDS/ADC CCD Video Processing ASIC MK-6.**  
*MSSL, UK & ESA/ESTEC, NL – P D Thomas / M R Hailey / R Harboe-Sørensen*
- 15:30**     **Coffee Break**

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15:45 - 19:00

- 15:45**    **Radiation SEE Evaluation of High Capacity FLASH Memory Devices for the SafeGuard Data Recorder.**  
*IDA, Germany – M Brüggemann / H Schmidt / D Walter / F Gliem / T Fichna*
- 16:00**    **Summary and Results of Enhanced Low Dose Rate Effects (ELDRS) Testing Performed at the ESTEC Co-60 Facility.**  
*ESA/ESTEC, NL - Cécile Renaudie / Bob Nickson / Ali Mohammadzadeh*
- 16:15**    **Summary and Results of Recent Proton Testing Carried Out on COTS Components for the LHC.**  
*CERN, Switzerland – Federico Faccio / Thijs Wijnands*
- 16:45**    **End of the Technical Programme.**
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- 19:00**    **Start of Social Programme – Dinner Boat Trip**